

# MBM600E17F

## Preliminary Specification

Silicon N-channel IGBT 1700V F version

### FEATURES

- \* \* Soft switching behavior, low switching loss & low conduction loss :  
Soft low-injection punch-through with trench gate IGBT
- \* Low driving power due to low input capacitance advanced trench MOS gate.
- \* Ultra soft fast recovery diode.
- \* Low  $R_{th(j-c)}$  & low stray inductance.
- \* High thermal fatigue durability

### ABSOLUTE MAXIMUM RATINGS ( $T_C=25^\circ\text{C}$ )

| Item                      | Symbol            | Unit             | MBM600E17F         |
|---------------------------|-------------------|------------------|--------------------|
| Collector Emitter Voltage | $V_{CES}$         | V                | 1,700              |
| Gate Emitter Voltage      | $V_{GES}$         | V                | $\pm 20$           |
| Collector Current         | DC                | A                | 600                |
|                           | 1ms               |                  | 1,200              |
| Forward Current           | DC                | A                | 600                |
|                           | 1ms               |                  | 1,200              |
| Junction Temperature      | $T_{vj,op}$       | $^\circ\text{C}$ | -50 ~ +150         |
| Storage Temperature       | $T_{stg}$         | $^\circ\text{C}$ | -50 ~ +125         |
| Isolation Voltage         | $V_{ISO}$         | $V_{RMS}$        | 4,000(AC 1 minute) |
| Screw Torque              | Terminals (M4/M8) | -                | 2/15 (1)           |
|                           | Mounting (M6)     | -                | 6 (2)              |

Notes: (1) Recommended Value  $1.8 \pm 0.2/15^{+0}_{-3} \text{N}\cdot\text{m}$  (2) Recommended Value  $5.5 \pm 0.5 \text{N}\cdot\text{m}$ 

### ELECTRICAL CHARACTERISTICS

| Item                                 | Symbol       | Unit          | Min. | Typ. | Max.  | Test Conditions   |                  |
|--------------------------------------|--------------|---------------|------|------|-------|---|------------------|
| Collector Emitter Cut-Off Current    | $I_{CES}$    | mA            | -    | -    | 5     | $V_{CE}=1,700\text{V}, V_{GE}=0\text{V}, T_{vj}=25^\circ\text{C}$               |                  |
|                                      |              |               | -    | 12   | 40    | $V_{CE}=1,700\text{V}, V_{GE}=0\text{V}, T_{vj}=150^\circ\text{C}$              |                  |
| Gate Emitter Leakage Current         | $I_{GES}$    | nA            | -500 | -    | +500  | $V_{GE}=\pm 20\text{V}, V_{CE}=0\text{V}, T_{vj}=25^\circ\text{C}$              |                  |
| Collector Emitter Saturation Voltage | $V_{CEsat}$  | V             | -    | 1.9  | -     | $I_C=600\text{A}, V_{GE}=15\text{V}, T_{vj}=25^\circ\text{C}$                   |                  |
|                                      |              |               | -    | 2.3  | TBD   | $I_C=600\text{A}, V_{GE}=15\text{V}, T_{vj}=150^\circ\text{C}$                  |                  |
| Gate Emitter Threshold Voltage       | $V_{GE(th)}$ | V             | 4.1  | 5.5  | 7.1   | $V_{CE}=10\text{V}, I_C=60\text{mA}, T_{vj}=25^\circ\text{C}$                   |                  |
| Input Capacitance                    | $C_{ies}$    | nF            | -    | 30   | -     | $V_{CE}=10\text{V}, V_{GE}=0\text{V}, f=100\text{kHz}, T_{vj}=25^\circ\text{C}$ |                  |
| Internal Gate Resistance             | $R_{G(int)}$ | $\Omega$      | -    | 8    | -     | $V_{CE}=10\text{V}, V_{GE}=0\text{V}, f=100\text{kHz}, T_{vj}=25^\circ\text{C}$ |                  |
| Turn On Delay Time                   | $t_{d(on)}$  | $\mu\text{s}$ | -    | 1.0  | TBD   | $V_{CC}=900\text{V}, I_C=600\text{A}$   |                  |
| Rise Time                            | $t_r$        |               | -    | 0.15 | TBD   | $L_S=100\text{nH}$ (3)  |                  |
| Turn Off Delay Time                  | $t_{d(off)}$ |               | -    | 1.3  | TBD   | $R_G(\text{on/off})=5.6/5.6\Omega$ (3)  |                  |
| Fall Time                            | $t_f$        |               | -    | 1.7  | TBD   | $V_{GE}=\pm 15\text{V}, T_{vj}=150^\circ\text{C}$                               |                  |
| Peak Forward Voltage Drop            | $V_F$        | V             | -    | 1.7  | -     | $I_F=600\text{A}, V_{GE}=0\text{V}, T_{vj}=25^\circ\text{C}$                    |                  |
|                                      |              |               | -    | 1.8  | -     | $I_F=600\text{A}, V_{GE}=0\text{V}, T_{vj}=150^\circ\text{C}$                   |                  |
| Reverse Recovery Time                | $t_{rr}$     | $\mu\text{s}$ | -    | 1.0  | -     | $V_{CC}=900\text{V}, I_C=600\text{A}$   |                  |
| Turn On Loss                         | $E_{on}$     | J/P           | -    | 0.21 | -     | $L_S=100\text{nH}$ (3)  |                  |
| Turn Off Loss                        | $E_{off}$    | J/P           | -    | 0.45 | -     | $R_G(\text{on/off})=5.6/5.6\Omega$ (3)  |                  |
| Reverse Recovery Loss                | $E_{rr}$     | J/P           | -    | 0.19 | -     | $V_{GE}=\pm 15\text{V}, T_{vj}=150^\circ\text{C}$                               |                  |
| Stray inductance module              | $L_{SCE}$    | nH            | -    | 21   | -     |   |                  |
| Thermal Impedance                    | IGBT         | $R_{th(j-c)}$ | K/W  | -    | -     | 0.038   | Junction to case |
|                                      | FWD          | $R_{th(f-c)}$ |      | -    | -     | 0.060   |                  |
| Contact Thermal Impedance            |              | $R_{th(c-f)}$ | K/W  | -    | 0.008 | -   | Case to fin      |

Notes:(3)  $L_S$  and  $R_G$  are the test condition's values for evaluation of the switching times, not recommended value.Please, determine the suitable  $R_G$  value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted.

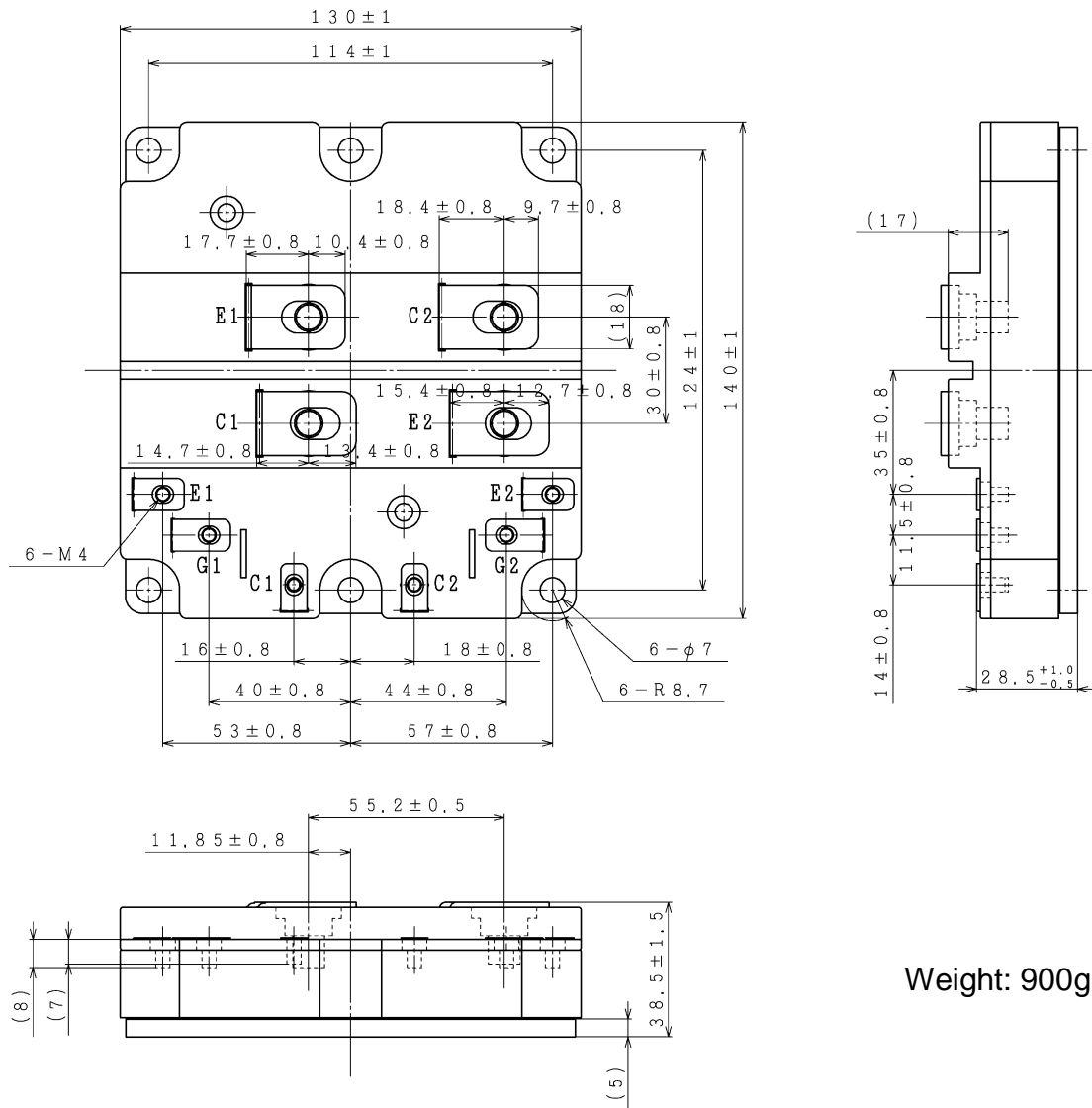
- \* Please contact our representatives at order.
- \* For improvement, specifications are subject to change without notice.
- \* For actual application, please confirm this spec sheet is the newest revision.
- \* ELECTRICAL CHARACTERISTIC items shown in above table are according to IEC 60747-2 and IEC 60747-9.

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Preliminary Specification

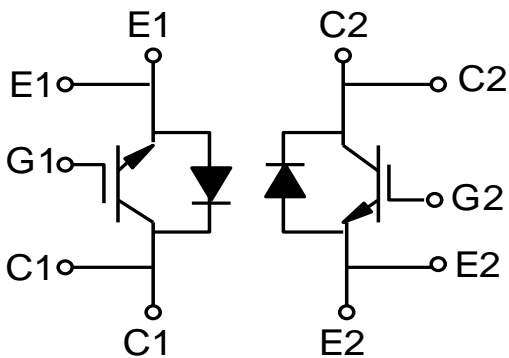
## OUTLINE DRAWING

Unit in mm



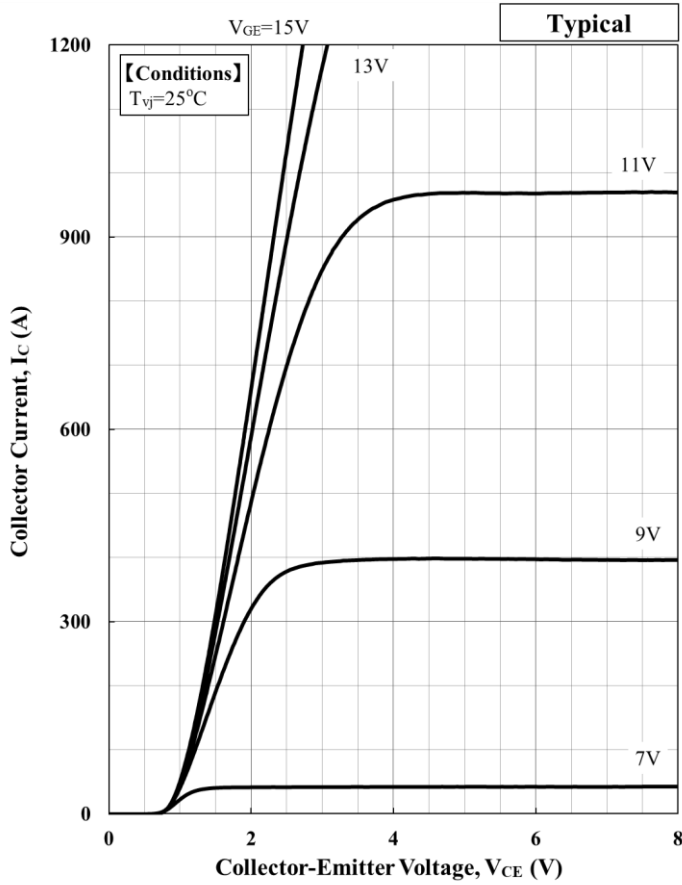
Weight: 900g

## CIRCUIT DIAGRAM

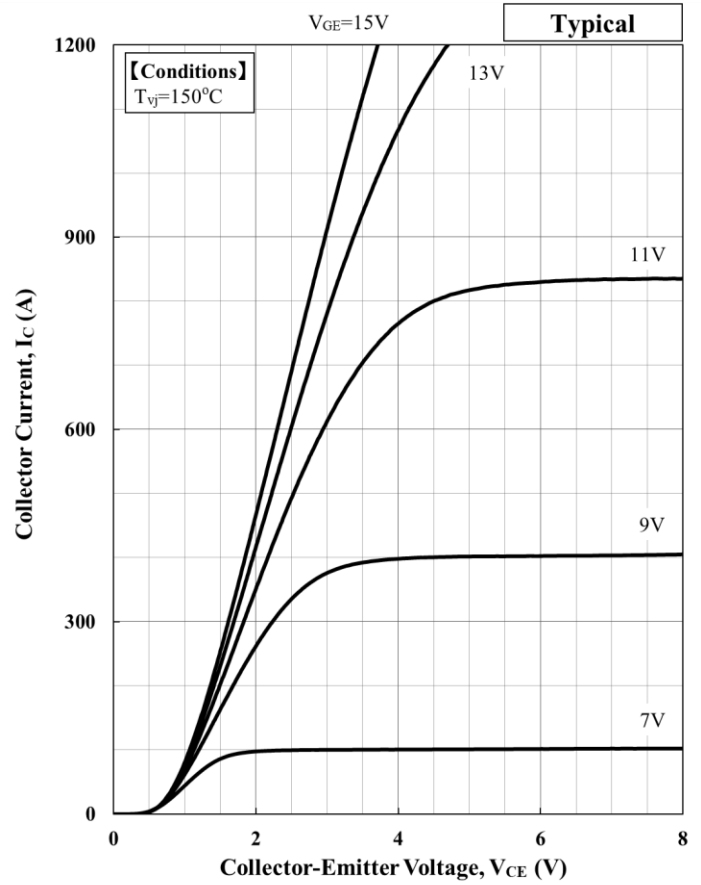


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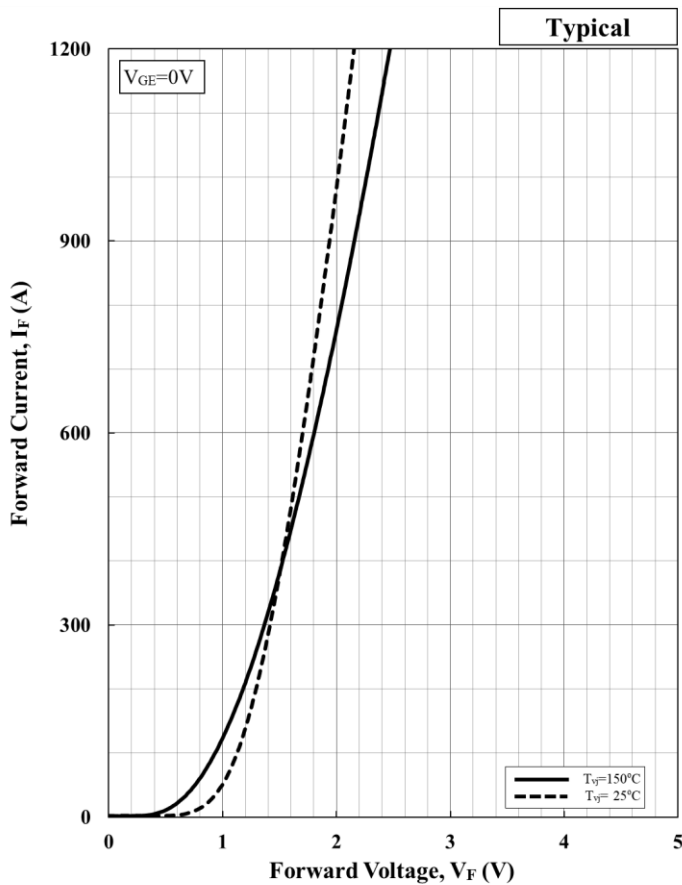
Preliminary Specification



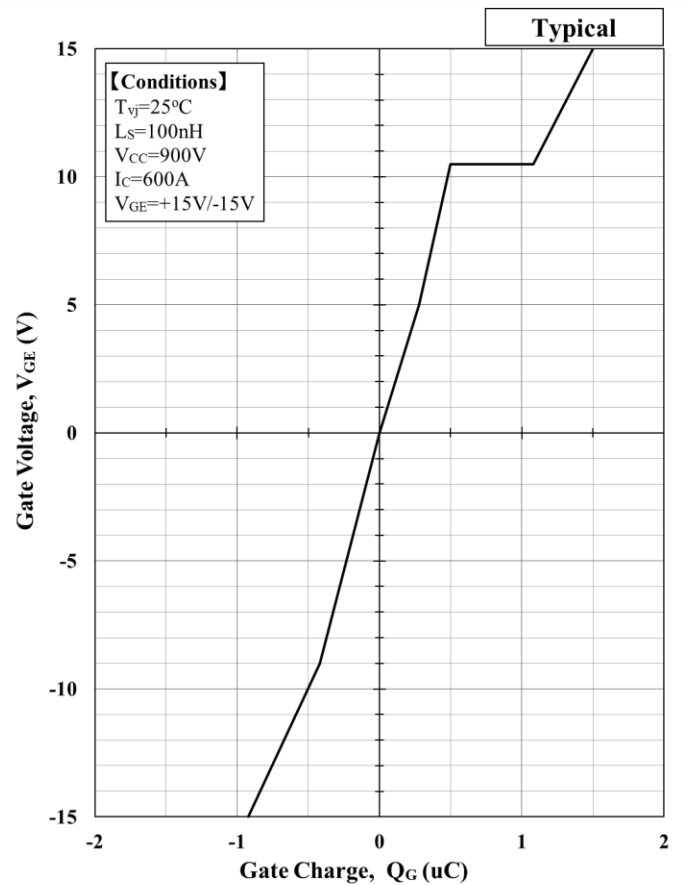
Collector Current vs. Collector Emitter Voltage



Collector Current vs. Collector Emitter Voltage



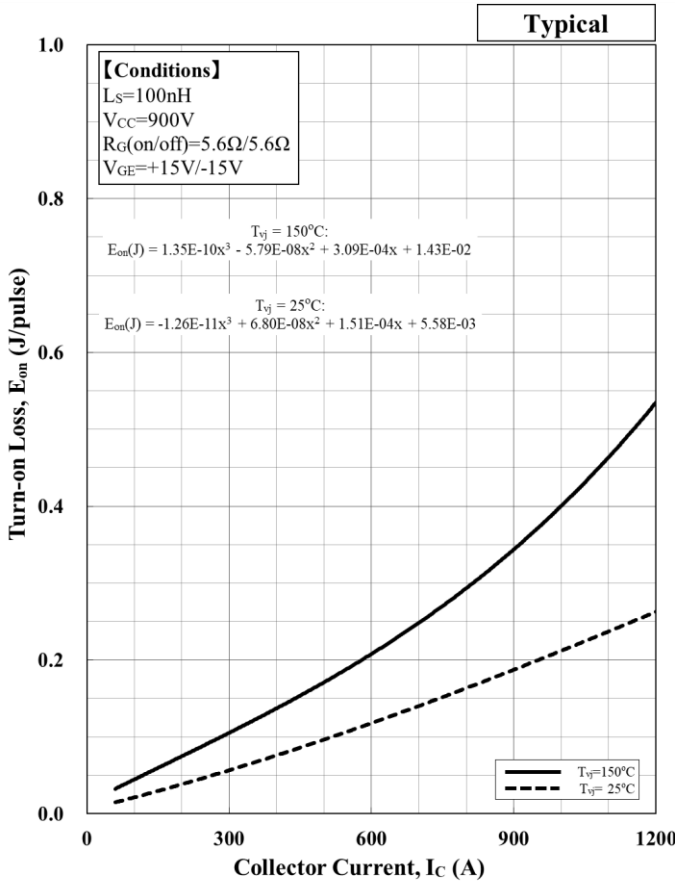
Forward Voltage of free-wheeling diode



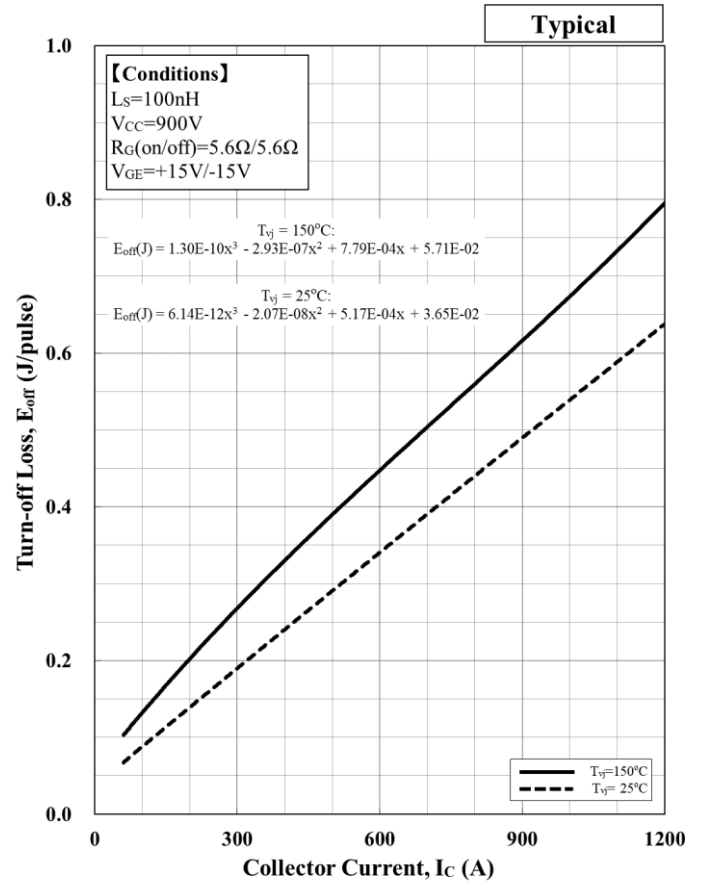
$V_{GE}-Q_G$  curve

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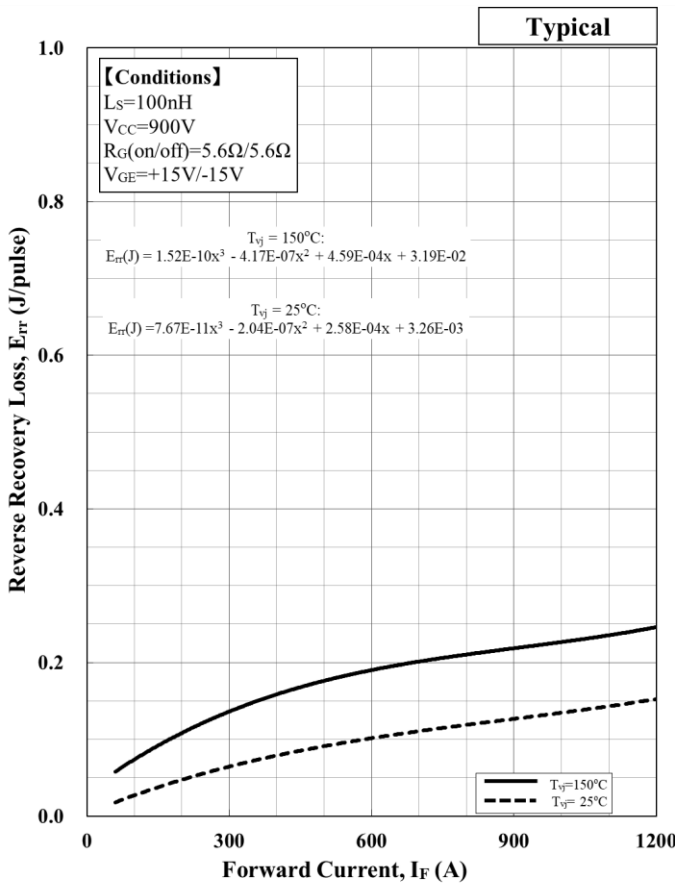
## Preliminary Specification



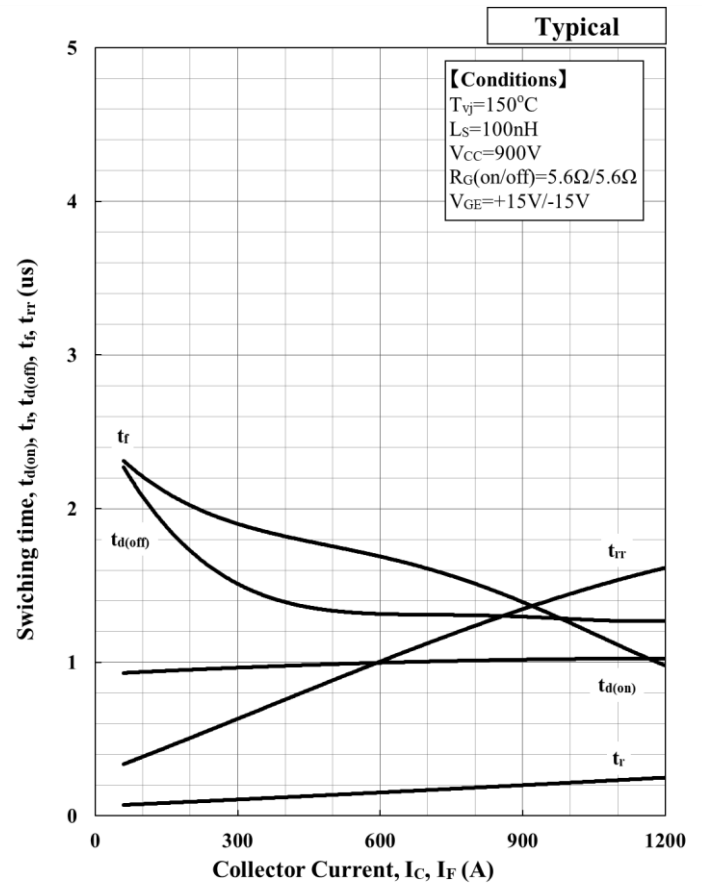
Turn-on loss vs. Collector current



Turn-off loss vs. Collector current



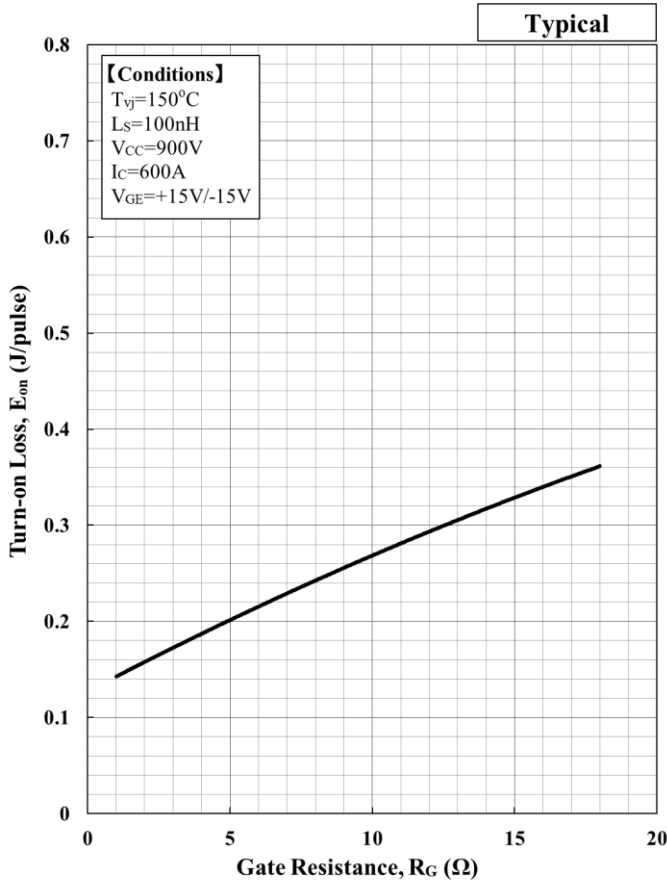
Recovery loss vs. Forward current



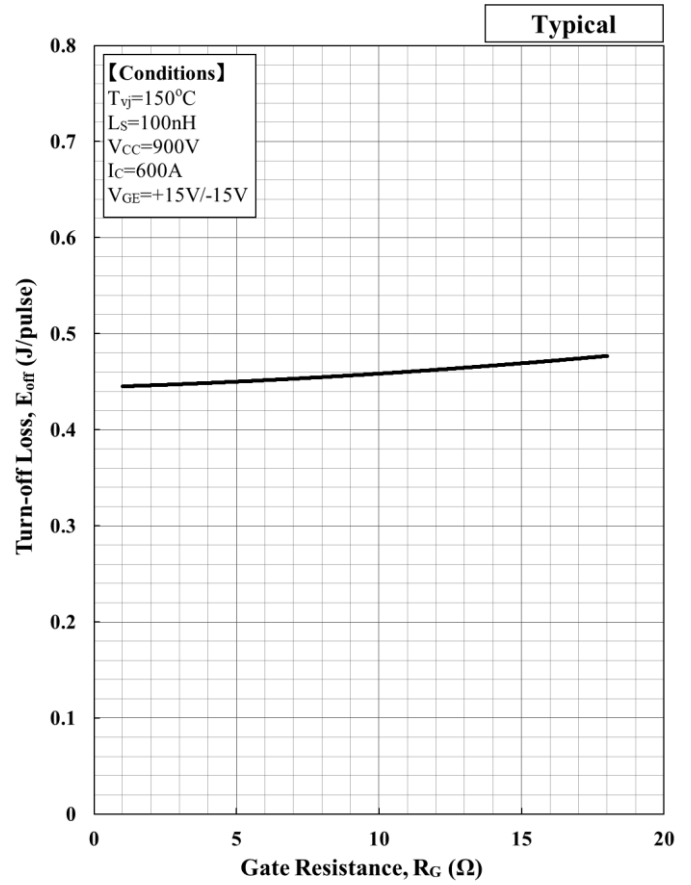
Switching time vs. Collector Current

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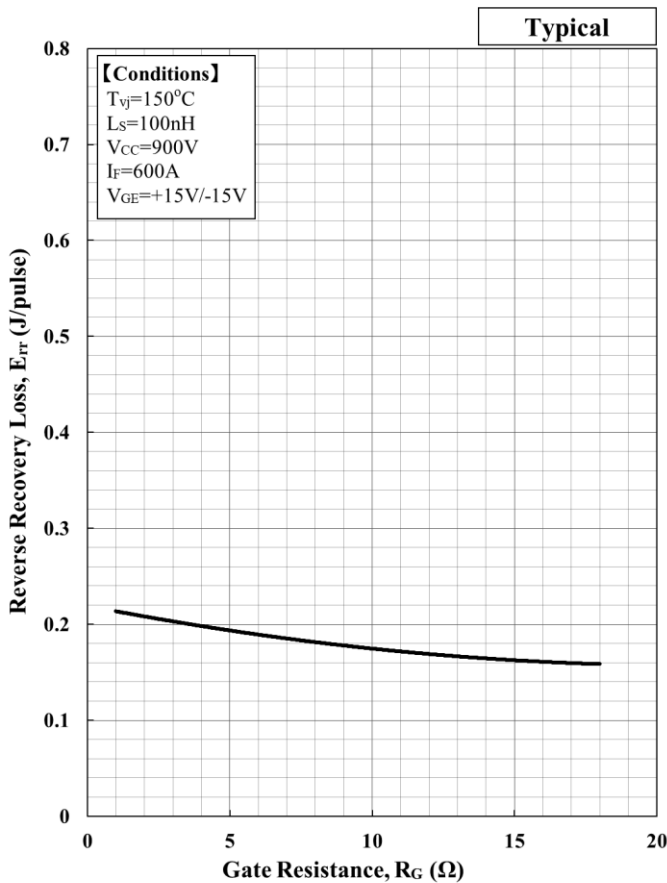
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Turn-on loss vs. Gate Resistance



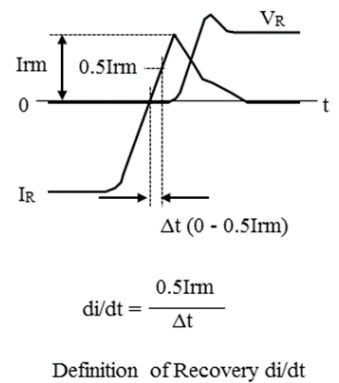
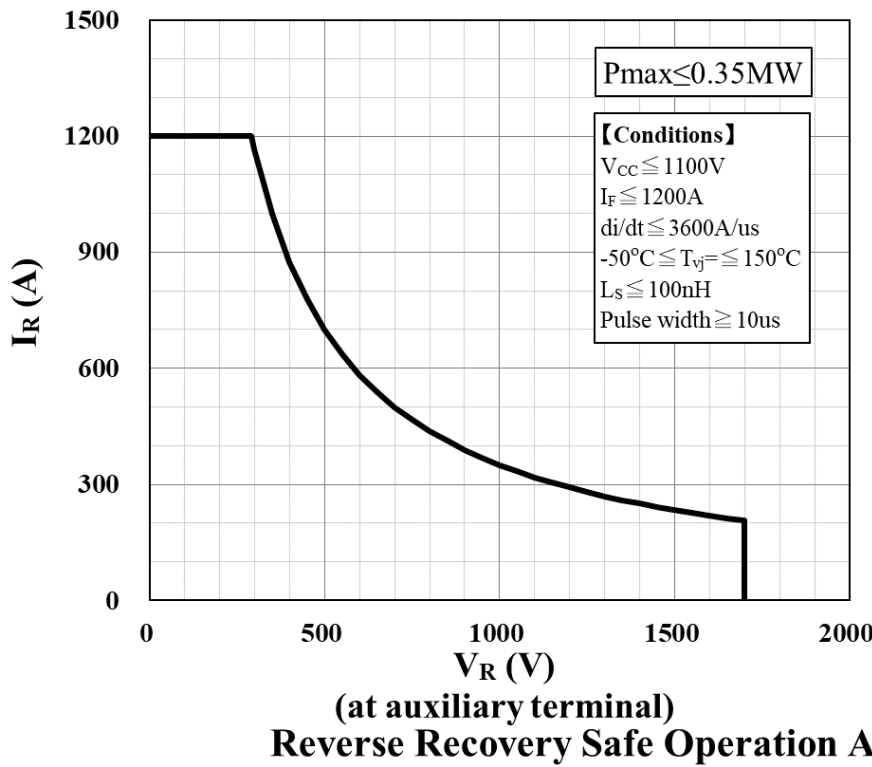
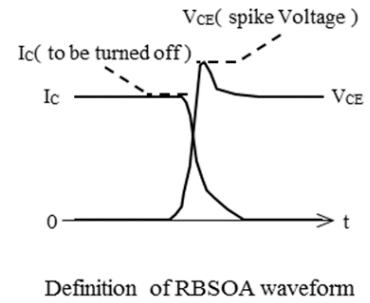
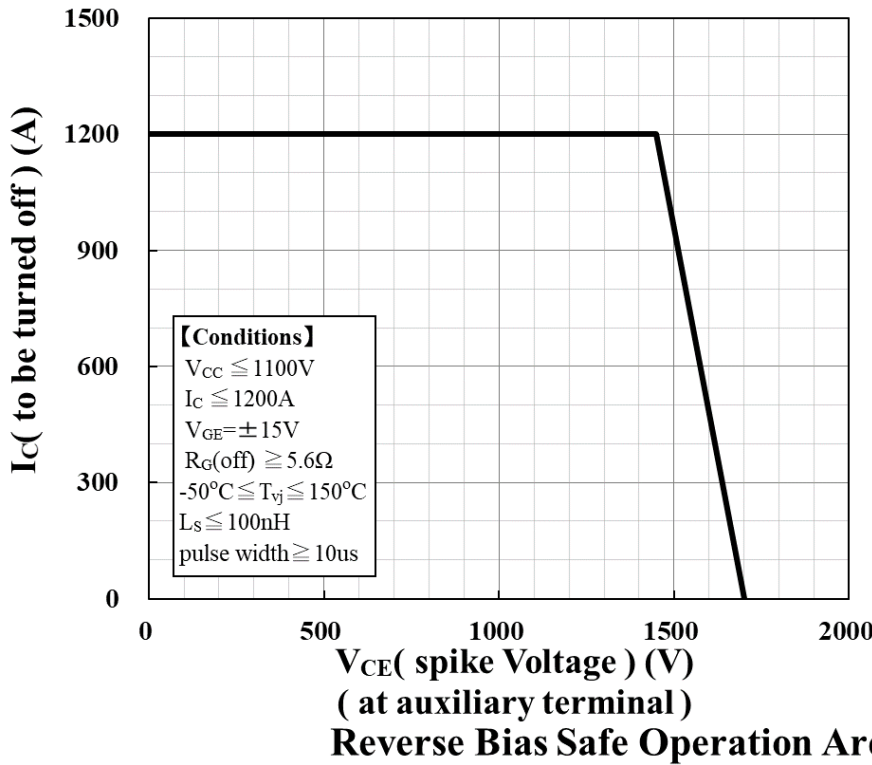
Turn-off loss vs. Gate Resistance



Recovery loss vs. Gate Resistance

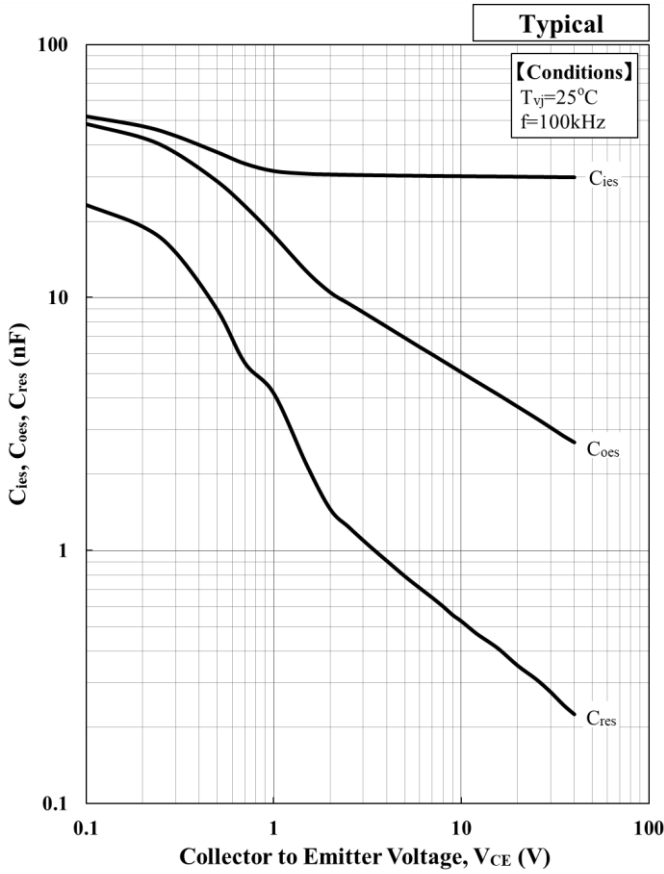
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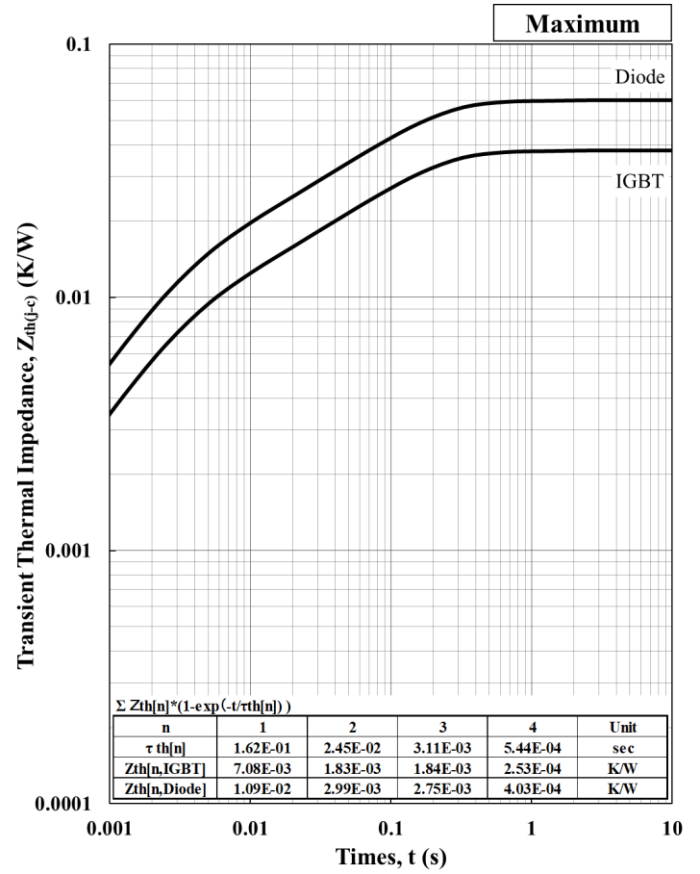


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## Preliminary Specification



Capacitance vs. Collector to Emitter Voltage



Transient Thermal Impedance Curve

### Material declaration

Please note the following materials are contained in the product, in order to keep characteristic and reliability level.

| Material                    | Contained part |
|-----------------------------|----------------|
| Lead (Pb) and its compounds | Solder         |

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Preliminary Specification

## HITACHI POWER SEMICONDUCTORS

### Notices

1. Since mishandling of semiconductor devices may cause malfunctions, please be sure to read "Precautions for Safe Use and Notices" in the individual brochure before use.
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4. In cases where extremely high reliability is required (such as use in nuclear power control, aerospace and aviation, traffic equipment, life-support-related medical equipment, fuel control equipment and various kinds of safety equipment), safety should be ensured by using semiconductor devices that feature assured safety or by means of users' fail-safe precautions or other arrangement. Or consult with Hitachi's sales department staff. (When semiconductor devices fail, as a result the semiconductor devices or wiring, wiring pattern may smoke, ignite, or the semiconductor devices themselves may burst.)
5. A semi-processed article is done now using solder which contains lead inside the semiconductor devices. There is possibility of the regulation substance depend on the applied models, so please check before using.
6. This specification is a material for component selection, which describes specifications of power semiconductor devices (hereinafter referred to as products), characteristic charts, and external dimension drawings.
7. The information given herein, including the specifications and dimensions, is subject to change without prior notice to improve product characteristics. Before ordering, purchasers are advised to contact with Hitachi power semiconductor sales department for the latest version of this data sheets.
8. For handling other than described in this manual, follow the handling instructions (IGBT-HI-00002).

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- For inquiries relating to the products, please contact nearest representatives that is located "Inquiry" portion on the top page of a home page.
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## HITACHI POWER SEMICONDUCTORS

### Usage

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